

#### A Possible Redundancy System for Opto-Links

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IBL General Meeting



#### Outline

- Implications of New Quarter Service Panel Project
- Result on Driver/Receiver Chips with redundancy
- Implication of Redundancy on other Sub-systems
- Summary

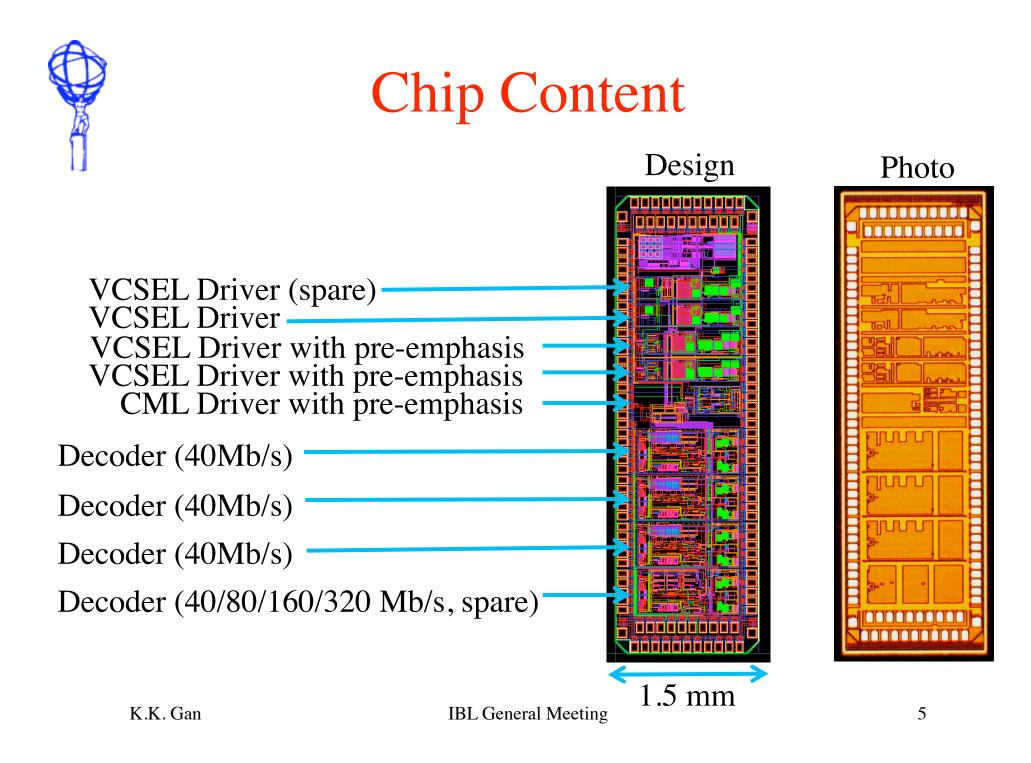
# Implications of New QSP Project

• New QSP Project pushes the opto-boards schedule forward:

- VCSEL/PIN opto-pack FDR ~ Feb 2011?
- opto-board FDR ~ March 2011?
- VCSEL/PIN opto-pack PRR ~ August 2011?
- opto-board PRR ~ August 2011?
- new opto-board will be designed to be compatible with IBL
  - a further improved opto-boards with redundancy etc.
    might still be used for B-layer and IBL

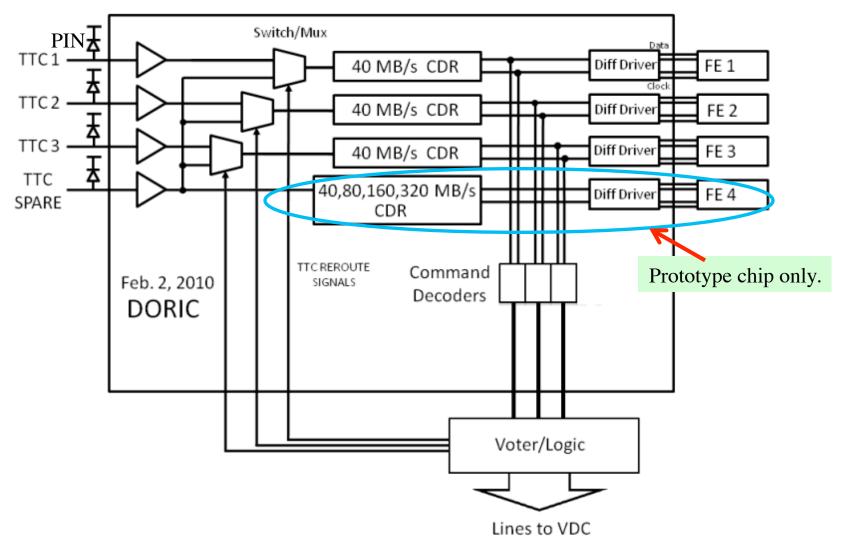
# Motivations for Redundancy

- Not yet learned how to build a highly reliable opto-links
  - $\sim 1.5\%$  of non operable pixel modules are links related
    - don't know the fraction of problematic links that are opto related
    - don't know how the problems will evolve with time
  - TXs for Pixel/SCT have been all replaced once
  - 194 out of 272 TXs of Pixel from second batch have been replaced
  - unlikely to get yearly access for opto-link repairs
  - some redundancy circuits developed will be useful for SLHC
  - ➡ redundancy allows operation of IBL with 100% efficiency





#### PIN Receiver/Decoder



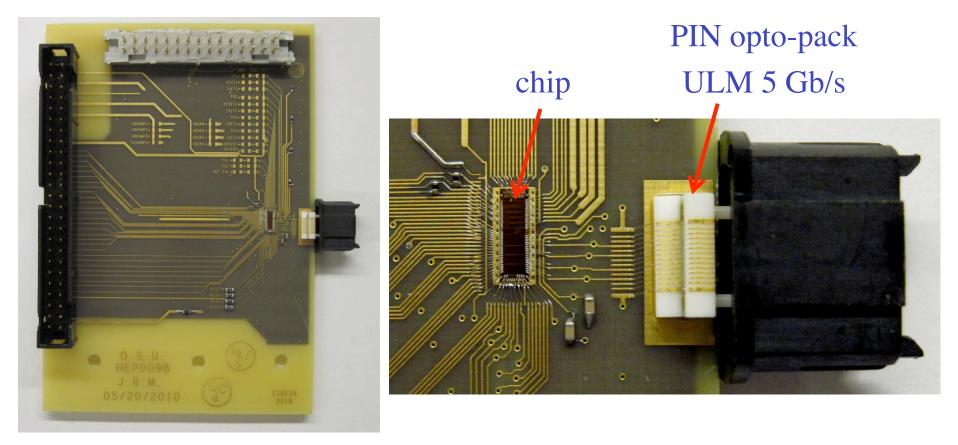
# **Command Decoder Interface**

Courtesy of FE-I4 of IBL Prototype: majority voting from 3 command decoders SEU Production: majority voting from up to 11 command decoders Command Hard Decoder 1 lobit Test Latch WR I Pads Address(25) Clock Decoder 1 In SEU SEU 16bit Serial In Command Hard Hard Data Parallel Out Voter Decoder 2 16bit 16bit In (Shift Register) Latch WR Latch Address(25) Reset Decoder 2 SEU In prototype Command Hard Write chip only Decoder 3 16bit Latch WR Address(25) Mode 16 x (2:1) MUX Decoder 3 Clock Out Serial Out Data Parallel In Out (Shift Register) Load STEER COMMAND STEER CH. SELECT SET DAC DAC VALUE VDC/DORIC WR (15)(14)(13)(12)(11:8)(7:0)Command Word K.K. Gan **IBL** General Meeting





#### Test card



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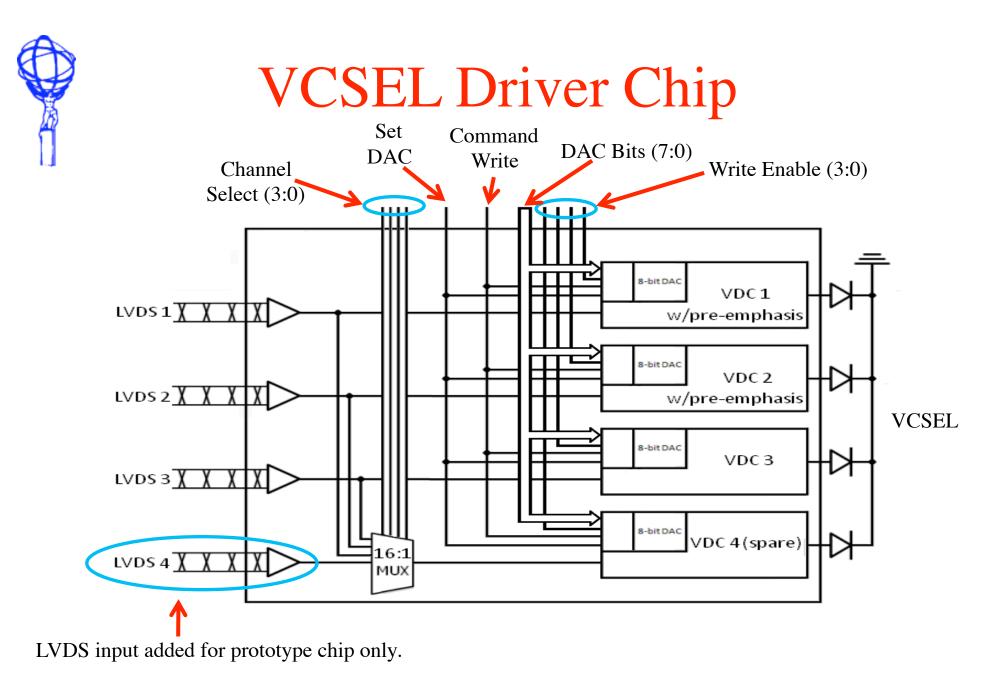
# Jitters/Thresholds

- ✓ Peak-to-peak clock jitter: 132 ps
- ✓ Threshold for no bit errors:
  - spare:  $40 \ \mu A$
  - **Ch** 1: 19 μA
  - **Ch** 2: 22 μA
  - **Ch** 3: 20 μA



#### PIN Receiver/Decoder

- ✓ All channels work at 40 Mb/s
- ✓ Steering signal to the spare channel works with test port
  - **x** steering via command decoder from FE-I4 not working
    - mis-communication between Ohio/Genova
    - ⇒ scan chain enable left floating



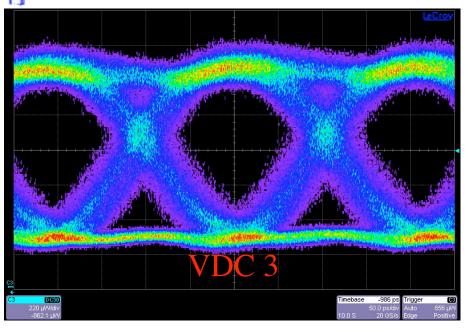


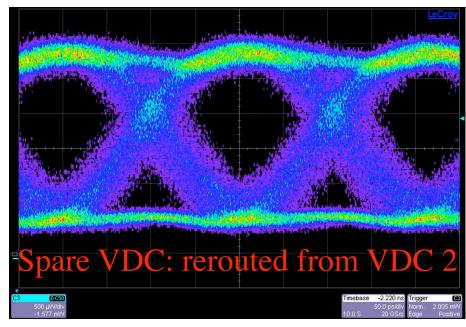
# **VDC** Results

- Power-on reset circuit
  - an open control line disables 6 opto-links in current pixel detector
    - ➡ implemented power-on reset circuit in prototype chip
    - ✓ chips power up with several mA of VCSEL current
- Test port
  - ✓ can steer signal received to spare VDC/VCSEL
  - ✓ can set DAC to control individual VCSEL currents
- ✓ All 4 channels run error free at 5 Gb/s
  - ✓ includes the spare with signal routed from the other LVDS inputs



# Eye Diagrams @ 4.8 Gb/s





- No pre-emphasis
- Rise/fall times: ~60-90 ps
  - Measured with 4.5 GHz optical probe
- Bit error rate  $< 5 \times 10^{-13}$

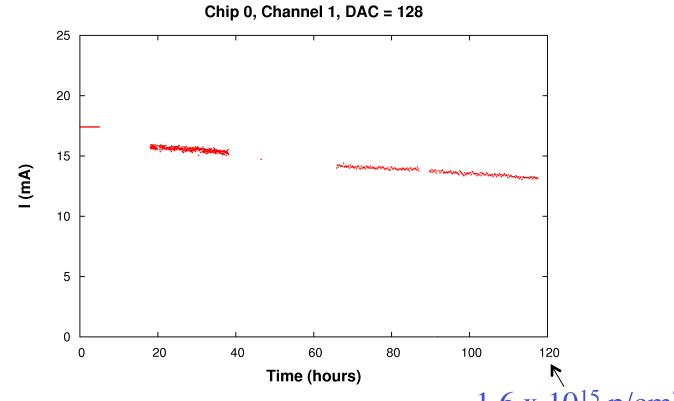


#### Irradiation

- 2 chips were packaged for irradiation with 24 GeV/c protons at CERN in August
  - each chip contains 4 channels of drivers and receivers
  - total dose: 1.6 x 10<sup>15</sup> protons/cm<sup>2</sup>
  - ◆ all testing are electrical to avoid complications from degradation of optical components
     ⇒ long cables limited testing to low speed
  - ✓ observe little degradation of devices
    - evaluation of full performance await return of devices to labs



# VDC Irradiation 2010



 $1.6 \text{ x } 10^{15} \text{ p/cm}^2$ 

- New VDC also drives 25  $\Omega$  with constant control current
- Decrease in drive current is small!
  - Fixed the problem observed in previous prototype



# Single Event Upset

- SEU harden latches or DAC could be upset by traversing particles
  - 126 latches per 4-channel chip
  - SEU tracked by monitoring the amplitude of VDC drive current
  - 13 instants (errors) of a channel steered
    to a urrang abannel in 71 bours for abin 4
    - to a wrong channel in 71 hours for chip #1
    - similar upset rate in chip #2
    - $\Rightarrow \sigma = 1 \times 10^{-16} \text{ cm}^2$
    - particle flux  $\sim 3x10^9$  cm<sup>-2</sup>/year @ opto-link location
    - $\Rightarrow$  SEU rate ~3x10<sup>-7</sup>/year/link



- FE: none
- Fibers: none
- Electrical service: need 1.5 V power supply
  - recommend: add wires for 1.5 V supply
  - working on regulator to derive 1.5 V from 2.5 V supply
- TX/BOC:
  - none if use fiber patch cords to reroute at USA15 to bypass dead links
  - recommend: 12-channel TX/BOC



#### Summary

• New QSP project advances IBL opto-links schedule significantly

- New 4-channel driver/receiver chips with redundancy and other improvements work well
- Propose to submit 12-channel version in February 2011